## Special Issue

## Signal Acquisition and Processing for Measurement and Testing

## Message from the Guest Editors

This Special Issue is devoted to the application of signal acquisition and processing in measurement and testing fields. The signal acquisition technique aims to acquire the analog signal, and it is governed by the Shannon sampling theorem. However, the rate of signal is usually high, and it brings a great challenge to the signal acquisition techniques. Therefore, the alternative signal acquisition techniques, such as sub-Nyquist sampling, compressive sampling etc., would be potential solutions to acquire the high speed signal. In this Special Issue, we will focus on the signal sampling methods and the corresponding processing techniques. The scope of submitted papers may encompass: (1) sampling models with mathematical explanations, particularly welcome will be models that could be implemented in circuitry. (2) signal reconstruction, representation and estimation; (3) design, circuitry implementation.

### **Guest Editors**

Prof. Dr. Yijiu Zhao

Prof. Dr. Yindong Xiao

Prof. Dr. Mingjiang Shi

## Deadline for manuscript submissions

closed (30 September 2024)



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## Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multidimensional network.

## Editor-in-Chief

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